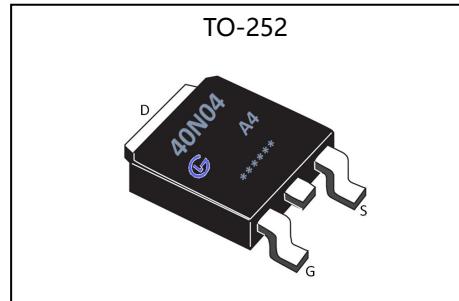


### General Description

The GL40N04A4 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is TO-252, which accords with the RoHS standard and two dies in this form.

V <sub>DSS</sub>	40	V
I <sub>D</sub>	40	A
P <sub>D</sub>	40	W
R <sub>DSON(TYP)</sub>	9.5	mΩ

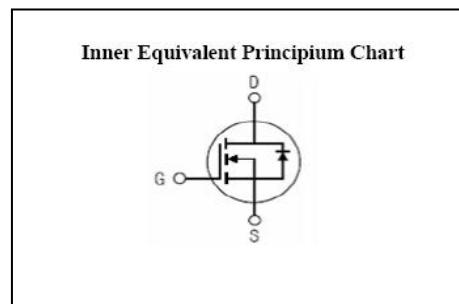


### Features

- Fast Switching
- Low Gate Charge and Rdson
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

### Applications

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



### Absolute (T<sub>c</sub>= 25°C unless otherwise specified)

Symbol	Parameter	Rating	Units
V <sub>DSS</sub>	Drain-to-Source Voltage	40	V
I <sub>D</sub>	Continuous Drain Current	40	A
	Continuous Drain Current T <sub>c</sub> = 100 °C	24	A
I <sub>DM</sub>	Pulsed Drain Current	80	A
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
E <sub>AS</sub> <sup>a2</sup>	Single Pulse Avalanche Energy	200	mJ
E <sub>AR</sub> <sup>a1</sup>	Avalanche Energy ,Repetitive	40	mJ
I <sub>AR</sub> <sup>a1</sup>	Avalanche Current	6	A
dv/dt <sup>a3</sup>	Peak Diode Recovery dv/dt	5.0	V/ns
P <sub>D</sub>	Power Dissipation	40	W
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction and Storage Temperature Range	150, -55 to 150	°C
T <sub>L</sub>	Maximum Temperature for Soldering	300	°C

Caution Stresses greater than those in the "Absolute Maximum Ratings" may cause permanent damage to the device



# GL40N04A4

## GL Silicon N-Channel Power MOSFET

**Electrical Characteristics** ( $T_c=25^\circ C$  unless otherwise specified)

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$V_{DSS}$	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40	--	--	V
$\Delta V_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu A$ , Reference $25^\circ C$	--	0.1	--	$V/^\circ C$
$I_{DSS}$	Drain to Source Leakage Current	$V_{DS}=40V, V_{GS}=0V, T_a=25^\circ C$	--	--	1	$\mu A$
		$V_{DS}=32V, V_{GS}=0V, T_a=125^\circ C$	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+20V$	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-20V$	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=20A$	--	9.5	13	$m\Omega$
		$V_{GS}=4.5V, I_D=10A$	--	13	18	$m\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.4	2.5	V
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$C_{iss}$	Input Capacitance	$V_{GS}=0V, V_{DS}=20V$ $f=1.0MHz$	--	960	--	pF
$C_{oss}$	Output Capacitance		--	100	--	
$C_{rss}$	Reverse Transfer Capacitance		--	95	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D=10A, V_{DD}=20V$ $V_{GS}=10V, R_G=3.0\Omega$	--	5.5	--	ns
$t_r$	Rise Time		--	14	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	24.0	--	
$t_f$	Fall Time		--	12	--	
$Q_g$	Total Gate Charge	$I_D=10A, V_{DD}=20V$ $V_{GS}=10V$	--	22	--	nC
$Q_{gs}$	Gate to Source Charge		--	3	--	
$Q_{gd}$	Gate to Drain ( "Miller" )Charge		--	5	--	

**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$I_S$	Continuous Source Current (Body Diode)		--	--	40	A
$I_{SM}$	Maximum Pulsed Current (Body Diode)		--	--	80	A
$V_{SD}$	Diode Forward Voltage	$I_S=10A, V_{GS}=0V$	--	--	1.5	V
$t_{rr}$	Reverse Recovery Time	$I_S=10A, T_j=25^\circ C$	--	30	--	ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt=100A/\mu s, V_{GS}=0V$	--	40	--	nC

 Pulse width  $t_p \leq 380\mu s, \delta \leq 2\%$ 
**Thermal Characteristics**

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Ambient	3.13	°C/W

<sup>a1</sup>: Repetitive rating; pulse width limited by maximum junction temperature

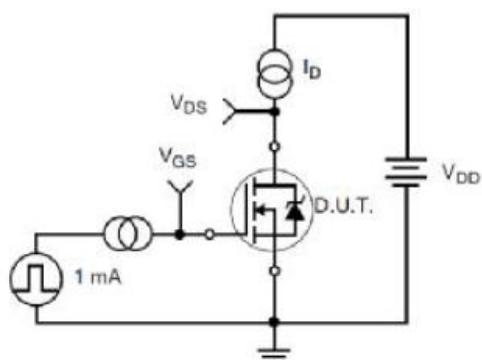
<sup>a2</sup>: EAS condition :  $T_j=25^\circ C$ ,  $V_{DD}=30V$ ,  $V_G=10V$ ,  $L=0.5mH$ ,  $R_g=25\Omega$ 
<sup>a3</sup>:  $I_{SD} = 10A, dI/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}$ , Start  $T_j=25^\circ C$ 
**Test Circuits**


Figure 17. Gate Charge Test Circuit

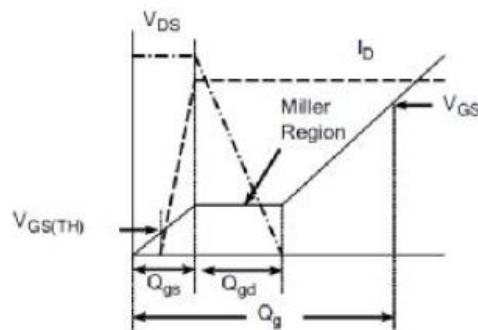


Figure 18. Gate Charge Waveform

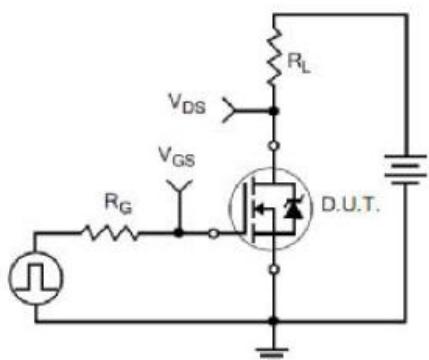


Figure 19. Resistive Switching Test Circuit

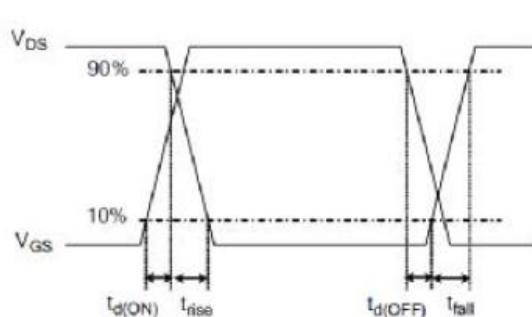
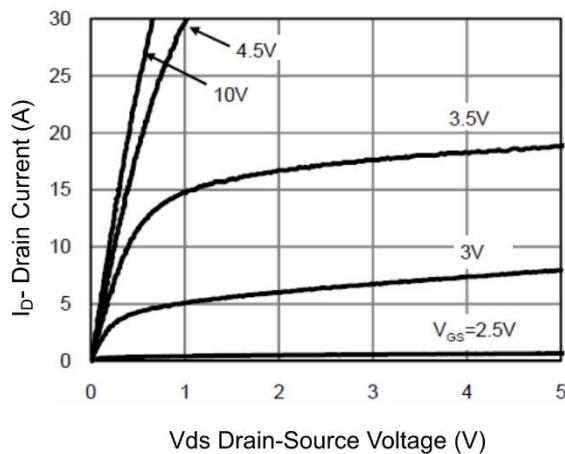
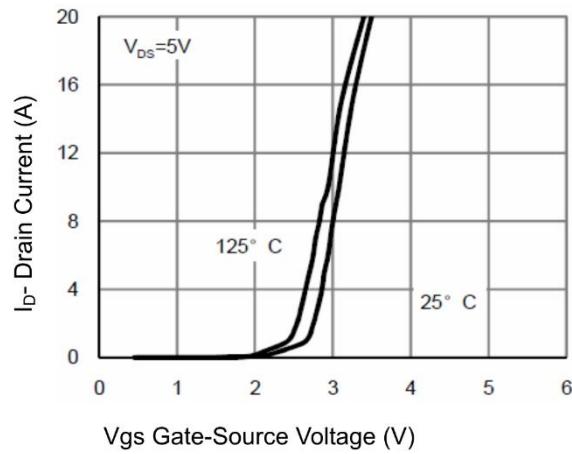


Figure 20. Resistive Switching Waveforms

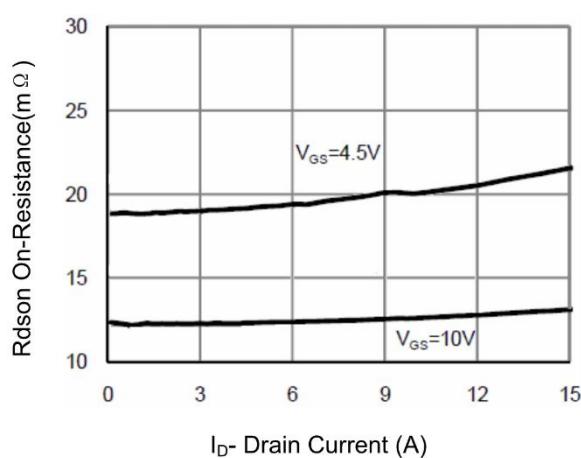
### Characteristics Curves



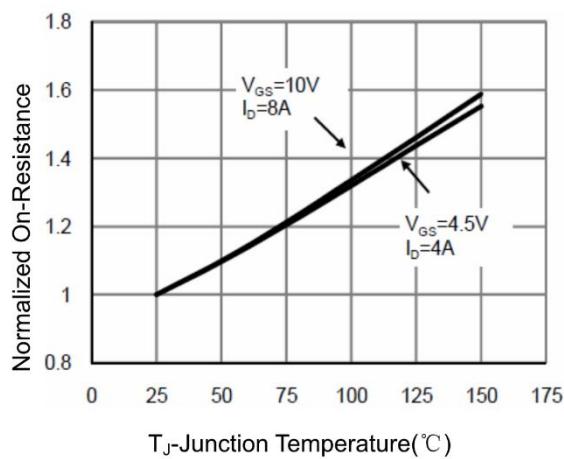
**Figure 1 Output Characteristics**



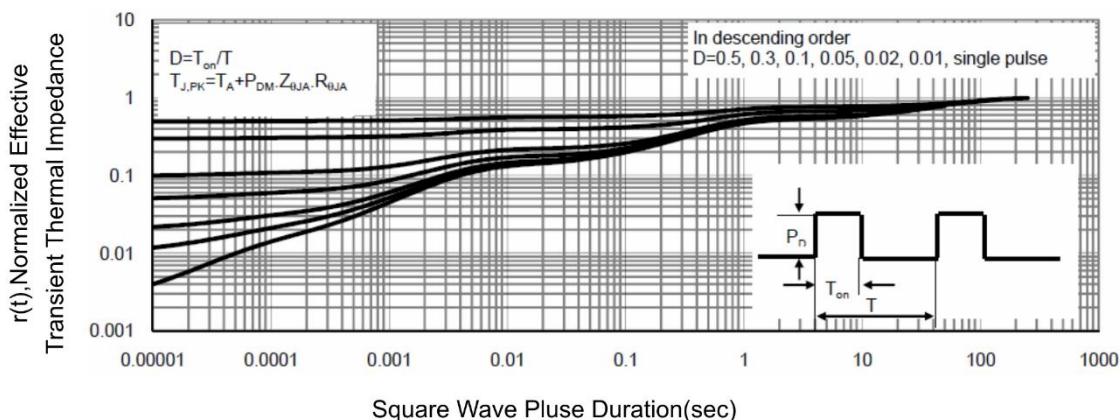
**Figure 2 Transfer Characteristics**



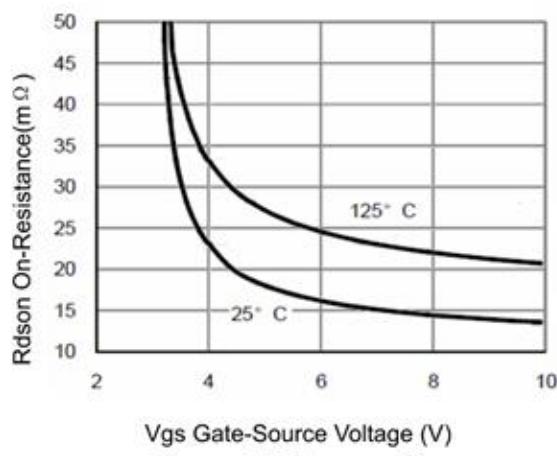
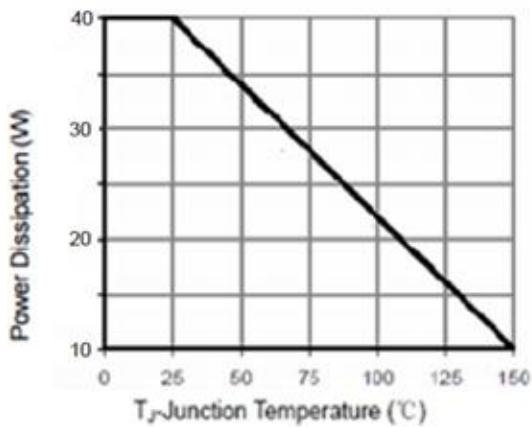
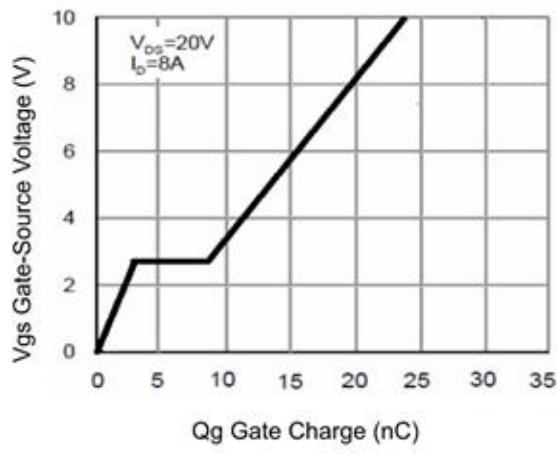
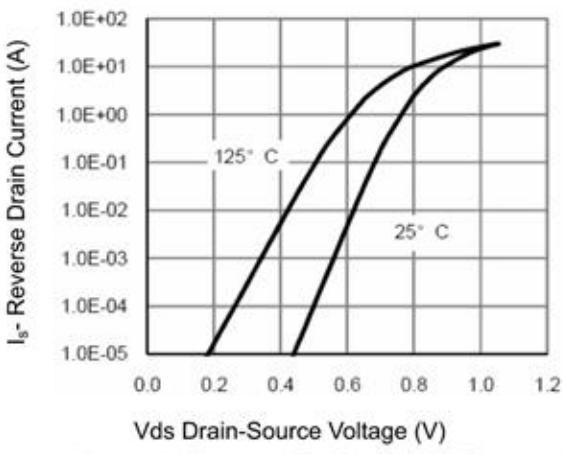
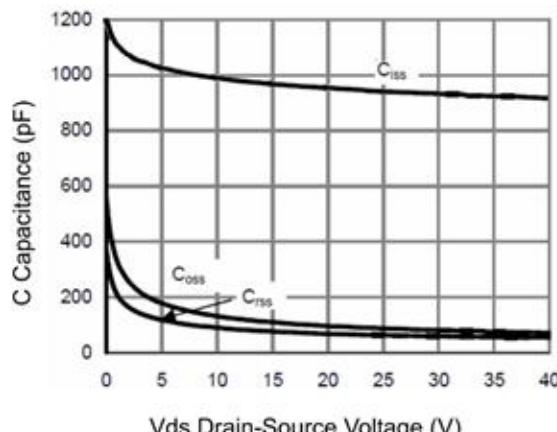
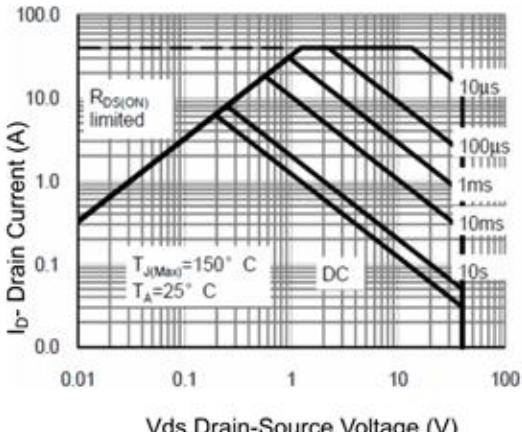
**Figure 3 Drain-Source On-Resistance**



**Figure 4 Drain-Source On-Resistance**



**Figure 5 Normalized Maximum Transient Thermal Impedance**


**Figure 6 Rdson vs Vgs**

**Figure 7 Power Dissipation**

**Figure 8 Gate Charge**

**Figure 9 Source- Drain Diode Forward**

**Figure 10 Capacitance vs Vds**

**Figure 11 Safe Operation Area**